



2/9/2017

**PRODUCT RELIABILITY REPORT
FOR**

DS1624

Maxim Integrated

**160 Rio Robles
San Jose, CA 95134**

Approved by:

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Conclusion:

The following qualification successfully meets the quality and reliability standards required of all Maxim products:

DS1624

In addition, Maxim's continuous reliability monitor program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards. The current status of the reliability monitor program can be viewed at <http://www.maxim-ic.com/TechSupport/dsreliability.html>.

Device Description:

A description of this device can be found in the product data sheet. You can find the product data sheet at http://dbserv.maxim-ic.com/l_datasheet3.cfm.

Reliability Derating:

The Arrhenius model will be used to determine the acceleration factor for failure mechanisms that are temperature accelerated.

$AfT = \exp((Ea/k)(1/T_u - 1/T_s)) = tu/ts$
AfT = Acceleration factor due to Temperature
tu = Time at use temperature (e.g. 55°C)
ts = Time at stress temperature (e.g. 125°C)
k = Boltzmann's Constant (8.617×10^{-5} eV/K)
Tu = Temperature at Use (°K)
Ts = Temperature at Stress (°K)
Ea = Activation Energy (e.g. 0.7 ev)

The activation energy of the failure mechanism is derived from either internal studies or industry accepted standards, or activation energy of 0.7ev will be used whenever actual failure mechanisms or their activation energies are unknown. All deratings will be done from the stress ambient temperature to the use ambient temperature.

An exponential model will be used to determine the acceleration factor for failure mechanisms, which are voltage accelerated.

$AfV = \exp(B(V_s - V_u))$
AfV = Acceleration factor due to Voltage
Vs = Stress Voltage (e.g. 7.0 volts)
Vu = Maximum Operating Voltage (e.g. 5.5 volts)
B = Constant related to failure mechanism type (e.g. 1.0, 2.4, 2.7, etc.)

The Constant, B, related to the failure mechanism is derived from either internal studies or industry accepted standards, or a B of 1.0 will be used whenever actual failure mechanisms or their B are unknown. All deratings will be done from the stress voltage to the maximum operating voltage. Failure rate data from the operating life test is reported using a Chi-Squared statistical model at the 60% or 90% confidence level (Cf).

The failure rate, Fr, is related to the acceleration during life test by:

$Fr = X/(ts * AfV * AfT * N * 2)$
X = Chi-Sq statistical upper limit
N = Life test sample size

Failure Rates are reported in FITs (Failures in Time) or MTTF (Mean Time To Failure). The FIT rate is related to MTTF by:

$$\text{MTTF} = 1/\text{Fr}$$

NOTE: MTTF is frequently used interchangeably with MTBF.

The calculated failure rate for this device/process is:

FAILURE RATE:	MTTF (YRS):	112374	FITS:	1.0
	DEVICE HOURS:	901990573	FAILS:	0

Only data from Operating Life or similar stresses are used for this calculation.

The parameters used to calculate this failure rate are as follows:

Cf: 60%	Ea: 0.7	B: 0	Tu: 25 °C	Vu: 5.5 Volts
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The reliability data follows. At the start of this data is the device information. The next section is the detailed reliability data for each stress. The reliability data section includes the latest data available and may contain some generic data. **Bold** Product Number denotes specific product data.

Device Information:

Process:	SA E35W-0.5um, 5V CMOS with embedded Array EEPROM, embedded RSE EEPROM, 18V CMOS, VNPN, P2-P1 Cap, LVMOSCAP, HVMOSCAP, Varactor Cap, NTC poly R's, 3LM, M3 Laser Fuses
Passivation:	TEOS Oxide-Nitride Passivation
Die Size:	68 x 80
Number of Transistors:	20125
Interconnect:	Aluminum / 0.5% Copper
Gate Oxide Thickness:	120 Å

ESD HBM

DESCRIPTION	DATE CODE/PRODUCT/LOT	CONDITION	READPOIN	QTY	FAILS	FA#
ESD SENSITIVITY	1009 DS1624	WJ048844B JESD22-A114 HBM 500 VOLTS	1	PUL'S	3	0
ESD SENSITIVITY	1009 DS1624	WJ048844B JESD22-A114 HBM 1000 VOLTS	1	PUL'S	3	0
ESD SENSITIVITY	1009 DS1624	WJ048844B JESD22-A114 HBM 2000 VOLTS	1	PUL'S	3	0
ESD SENSITIVITY	1009 DS1624	WJ048844B JESD22-A114 HBM 3000 VOLTS	1	PUL'S	3	0
ESD SENSITIVITY	1009 DS1624	WJ048844B JESD22-A114 HBM 4000 VOLTS	1	PUL'S	3	0
Total:						0

LATCH-UP

DESCRIPTION	DATE CODE/PRODUCT/LOT	CONDITION	READPOIN	QTY	FAILS	FA#
LATCH-UP I	1009 DS1624	WJ048844B JESD78A, I-TEST 125C		6	0	
LATCH-UP V	1009 DS1624	WJ048844B JESD78A, V-SUPPLY TEST 125C		6	0	
Total:						0

OPERATING LIFE

DESCRIPTION	DATE CODE/PRODUCT/LOT			CONDITION	READPOIN	QTY	FAILS	FA#
HIGH TEMP OP LIFE	0839	DS2784		WJ942986T 125C, 4.6 V (PSA) & 15.0 V (PSB)	1000 HRS	77	0	
HIGH TEMP OP LIFE	0843	DS2784		WJ941766O 125C, 4.6 V (PSA) & 15.0 V (PSB)	1000 HRS	77	0	
HIGH TEMP OP LIFE	0848	DS2784		WJ943239LC 125C, 4.6 V (PSA) & 15.0 V (PSB)	1000 HRS	77	0	
HIGH TEMP OP LIFE	0914	DS2780		WJ944804A 125C, 5.5 VOLTS	1000 HRS	77	0	
HIGH TEMP OP LIFE	0916	DS2784		WJ943240IC 125C, 5.5 V (PSA) & 15.0 V (PSB)	1000 HRS	77	0	
HIGH TEMP OP LIFE	0916	DS2784		WJ945481A 125C, 5.5 V (PSA) & 15.0 V (PSB)	1000 HRS	77	0	
HIGH TEMP OP LIFE	0922	DS36A92		WJ946542A 125C, 3.6 VOLTS	192 HRS	45	0	
HIGH TEMP OP LIFE	0932	MAX17043		WJ946441P 125C, 4.5V (PSA) & 9.2V (PSB)	192 HRS	45	0	
HIGH TEMP OP LIFE	0933	DS1873		QJ917612BC 125C, 4.2 VOLTS	192 HRS	77	0	
HIGH TEMP OP LIFE	0937	DS2784		WJ046898JC 125C, 5.5 V (PSA) & 15.0 V (PSB)	1000 HRS	77	0	
HIGH TEMP OP LIFE	0940	DS2784		WJ048759A 125C, 5.5 V (PSA) & 15.0 V (PSB)	1000 HRS	80	0	
HIGH TEMP OP LIFE	0946	DS1876		WJ048840A 125C, 4.2 VOLTS	192 HRS	77	0	
HIGH TEMP OP LIFE	0948	DS1091L		WJ946344E 150C, 3.6 VOLTS	408 HRS	45	0	
HIGH TEMP OP LIFE	0948	DS1091L		WJ946344E 150C, 3.6 VOLTS	408 HRS	45	0	
HIGH TEMP OP LIFE	0951	DS2784		WJ049559A 125C, 5.5 V (PSA) & 15.0 V (PSB)	1000 HRS	80	0	
HIGH TEMP OP LIFE	0951	DS1877		WJ048842A 125C, 4.2 VOLTS	192 HRS	77	0	
HIGH TEMP OP LIFE	0951	DS2430A		WH048838A 125C, 5.25 VOLTS	192 HRS	50	0	
HIGH TEMP OP LIFE	1004	DS3644		WS046549D 125C, 3.6V (PSA) & 3.3V (PSB)	192 HRS	45	0	
HIGH TEMP OP LIFE	1009	DS1624		WJ048844B 125C, 5.5 VOLTS	192 HRS	77	0	
HIGH TEMP OP LIFE	1013	DS2784		WJ050375A 125C, 5.5 V (PSA) & 15.0 V (PSB)	500 HRS	80	0	
Total:							0	

W/E ENDURANCE AND DATA RET'N

DESCRIPTION	DATE CODE/PRODUCT/LOT			CONDITION	READPOIN	QTY	FAILS	FA#
WRITE CYCLE STRESS (KCYS)	0839	DS2784		WJ942986T 50 C, 4.6 V (PSA) & 15.0 V (PSB)	50 KCYS	77	0	
STORAGE LIFE	0839	DS2784		WJ942986T 150C	1000 HRS	77	0	
WRITE CYCLE STRESS (KCYS)	0843	DS2784		WJ941766O 50 C, 4.6 V (PSA) & 15.0 V (PSB)	50 KCYS	77	0	

STORAGE LIFE	0843	DS2784	WJ941766O 150C	1000	HRS	77	0
WRITE CYCLE STRESS (KCYS)	0848	DS2784	WJ943239LC 50 C, 4.6 V (PSA) & 15.0 V (PSB)	50	KCYS	77	0
STORAGE LIFE	0848	DS2784	WJ943239LC 150C	1000	HRS	77	0
WRITE CYCLE STRESS (KCYS)	0916	DS2784	WJ943240IC 50 C, 5.5 V (PSA) & 15.0 V (PSB)	50	KCYS	77	0
STORAGE LIFE	0916	DS2784	WJ943240IC 150C	1000	HRS	77	0
WRITE CYCLE STRESS (KCYS)	0916	DS2784	WJ945481A 50 C, 5.5 V (PSA) & 15.0 V (PSB)	50	KCYS	77	0
STORAGE LIFE	0916	DS2784	WJ945481A 150C	1000	HRS	77	0
WRITE CYCLE STRESS (KCYS)	0940	DS3882	WJ946345A 85 C, 5.25 VOLTS	30	KCYS	77	0
STORAGE LIFE	0940	DS3882	WJ946345A 150C	1000	HRS	77	0
WRITE CYCLE STRESS (KCYS)	0951	DS2430A	WH048838A 25 C, 5.25 VOLTS	200	KCYS	77	0
STORAGE LIFE	0951	DS2430A	WH048838A 150C	96	HRS	77	0
WRITE CYCLE STRESS (KCYS)	1009	DS1624	WJ048844B 85 C, 5.5 VOLTS	25	KCYS	77	0
STORAGE LIFE	1009	DS1624	WJ048844B 150C	96	HRS	77	0
				Total:			0
FAILURE RATE:		MTTF (YRS):	112374	FITS:		1.0	
		DEVICE HOURS:	901990573	FAILS:		0	